

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE



Membership Publications/Services Standards Conferences Careers/Jobs

 Welcome
 United States Patent and Trademark Office


» See

[Help](#) | [FAQ](#) | [Terms](#) | [IEEE Peer Review](#)
[Quick Links](#)

Welcome to IEEE Xplore®

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced
- ☐ CrossRef

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

IEEE Enterprise

- ☐ Access the IEEE Enterprise File Cabinet

Print Format

Your search matched **3** of **1094442** documents.A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance Descending** order.**Refine This Search:**

You may refine your search by editing the current search expression or entering a new one in the text box.

digital pen

Search

☐ Check to search within this result set**Results Key:****JNL** = Journal or Magazine **CNF** = Conference **STD** = Standard**1 Variorum: a multimedia-based program documentation system**

Chiueh, T.; Wu, W.; Lam, L.-C.;

Multimedia and Expo, 2000. ICME 2000. 2000 IEEE International Conference on , Volume: 1 , 30 July-2 Aug. 2000
Pages:155 - 158 vol.1
[\[Abstract\]](#) [\[PDF Full-Text \(540 KB\)\]](#) IEEE CNF
2 Lectern: a digital desk system for video-free course-lecture capturing and playback

Chiueh, T.; Deng, P.;

Multimedia and Expo, 2000. ICME 2000. 2000 IEEE International Conference on , Volume: 1 , 30 July-2 Aug. 2000
Pages:3 - 6 vol.1
[\[Abstract\]](#) [\[PDF Full-Text \(500 KB\)\]](#) IEEE CNF
3 Automatic signature verification based on the dynamic feature of pressure

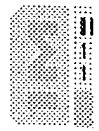
Tanabe, K.; Yoshihara, M.; Kameya, S.; Mori, S.; Omata, S.; Ito, T.;

Document Analysis and Recognition, 2001. Proceedings. Sixth International Conference on , 10-13 Sept. 2001
Pages:1045 - 1049
[\[Abstract\]](#) [\[PDF Full-Text \(376 KB\)\]](#) IEEE CNF

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

[IEEE HOME](#) | [SEARCH IEEE](#) | [SHOP](#) | [WEB ACCOUNT](#) | [CONTACT IEEE](#)

[Membership](#) | [Publications/Services](#) | [Standards](#) | [Conferences](#) | [Careers/Jobs](#)
IEEE Xplore
RELEASE 1.3

 Welcome
 United States Patent and Trademark Office


» See

[Help](#) | [FAQ](#) | [Terms](#) | [IEEE Peer Review](#)
[Quick Links](#)
Welcome to IEEE Xplore

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced
- ☐ CrossRef

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

IEEE Enterprise

- ☐ Access the IEEE Enterprise File Cabinet

Print Format

 Your search matched **0** of **1094442** documents.

 A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance Descending** order.

Refine This Search:

You may refine your search by editing the current search expression or entering a new one in the text box.

☐ Check to search within this result set

Results Key:
JNL = Journal or Magazine **CNF** = Conference **STD** = Standard

Results:
No documents matched your query.
[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved